



ALICE ITS Upgrade Pixel Chip Status

LHCC Detector Upgrade Review

CERN, 03 March 2015

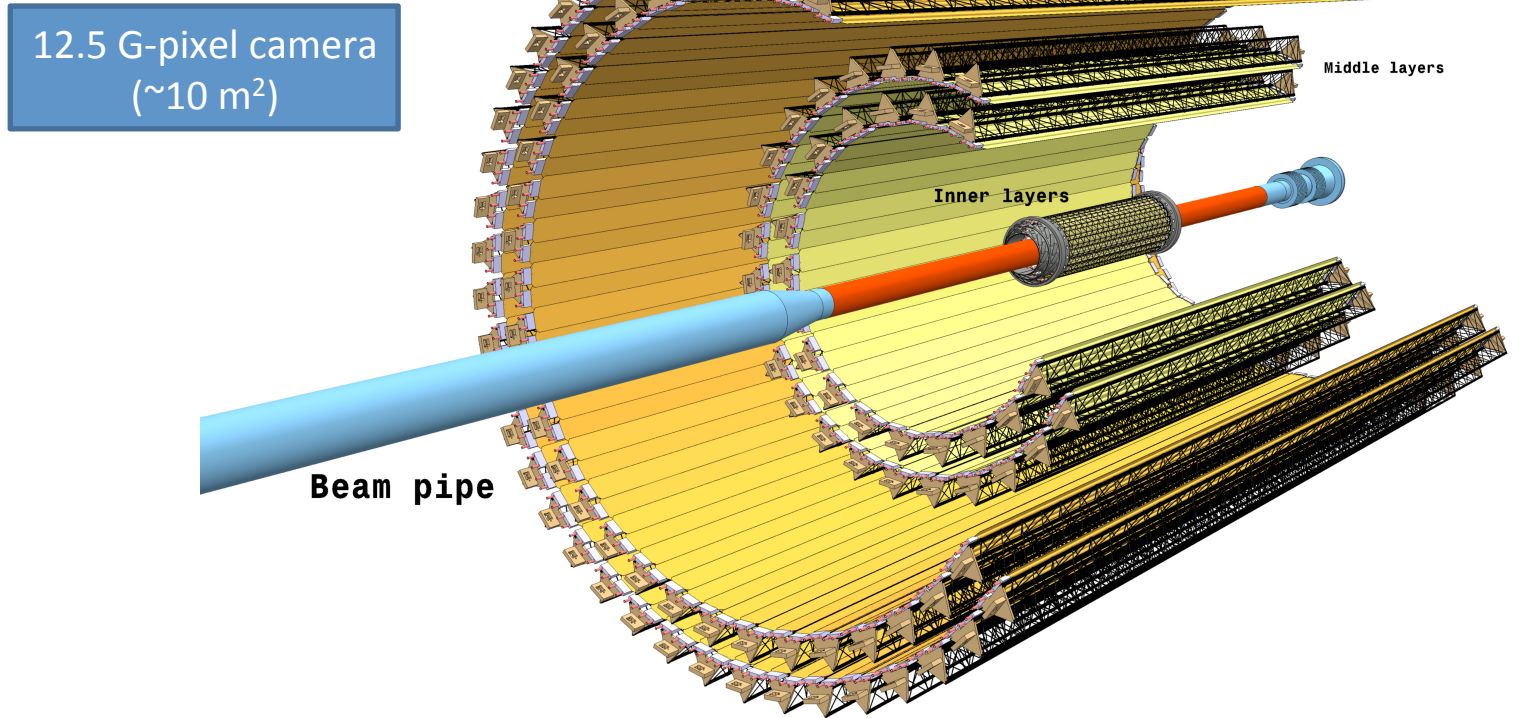
L. Musa - CERN

ALICE ITS Upgrade – Pixel Chip Status



OUTLINE

- ⦿ Pixel Chip Requirements
- ⦿ Two alternative architectures: ALPIDE and MISTRAL
- ⦿ ALPIDE
 - Design roadmap
 - p-ALPIDE-1 (full-scale prototype) results
- ⦿ MISTRAL-O
 - Design roadmap
 - MISTRAL FSBB (full-scale building block) results
- ⦿ Conclusions



7-layer barrel geometry based on MAPS

r coverage: 23 – 400 mm

η coverage: $|\eta| \leq 1.22$

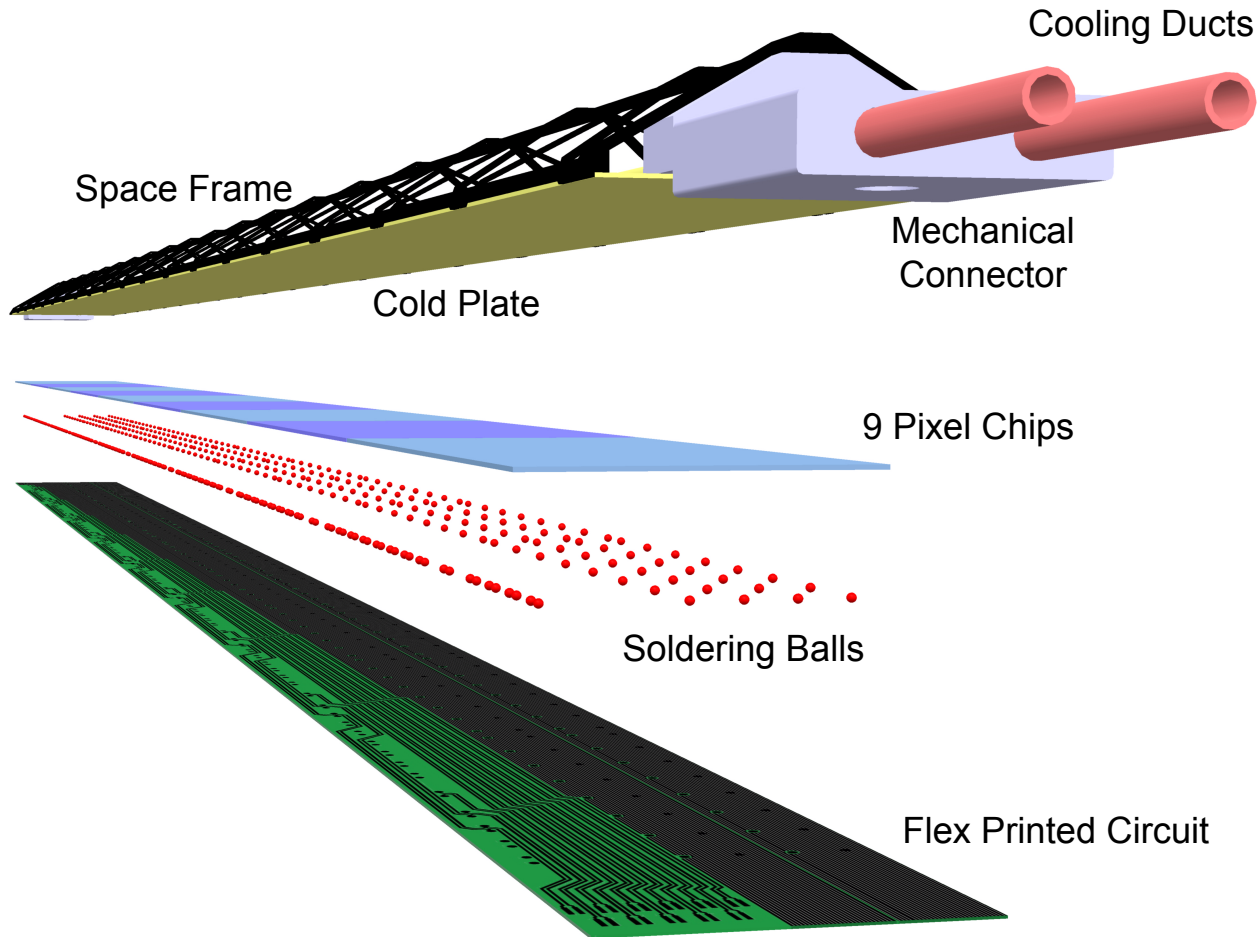
for tracks from 90% most luminous region

3 Inner Barrel layers (**IB**)

4 Outer Barrel layers (**OB**)

Material /layer : 0.3% X_0 (IB), 1% X_0 (OB)

Inner Barrel Stave



PIXEL Chip – General Requirements



Parameter	Inner Barrel	Outer Barrel
Max silicon thickness	50 μm	
spatial resolution	5 μm	10 μm
chip dimensions	15 mm x 30 mm	
Max power density	300 mW/cm ²	100 mW/cm ²
Max event time resolution	< 30 μs	
Min detection efficiency	> 99%	
Max fake hit rate	< 10 ⁻⁵ per readout frame	
TID radiation hardness (*)	700 krad (TDR) 2700 krad (rev Dec 14)	10 krad (TDR) 100 krad (rev Dec 14)
NIEL radiation hardness (*)	10 ¹³ 1MeV n _{eq} /cm ² (TDR) 1.7x10 ¹³ 1MeV n _{eq} /cm ² (rev)	3x10 ¹¹ 1MeV n _{eq} /cm ² (TDR) 10 ¹² 1MeV n _{eq} /cm ² (rev)

(*) 10 x radiation load integrated over approved programme (~ 6 years of operation)

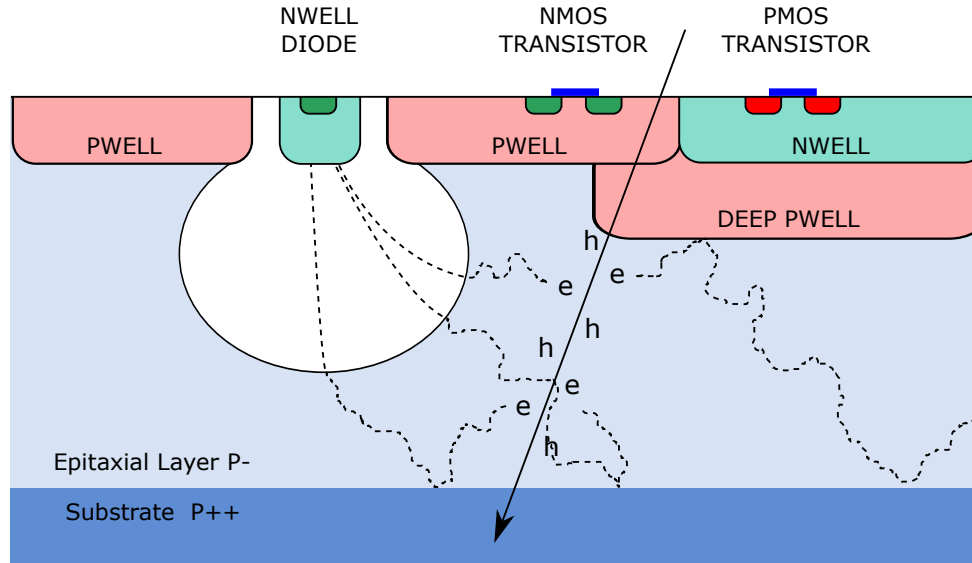
Genesis

- Owing to the intensive R&D work on CMOS pixel sensors carried out by IPHC (... and the vision and support of STAR) over the last 15 years
- ☛ First monolithic pixel detector in a HEP experiment (STAR HFT detector)
- Based on AMS 0.35 μ m twin-well CMOS process
- Readout speed and radiation hardness not adequate for ALICE ITS upgrade

The industrial development of CMOS imaging sensors (e.g. TowerJazz CIS) + R&D work from RAL and IPHC

- ☛ development of first exploratory pixel chips based on a quadruple-well 0.18 μ m CMOS Imaging Sensor (CIS) process
- ☛ based on the R&D work of IPHC in 2011 and 2012, ALICE decided to adopt MAPS as baseline technology for the ITS upgrade (LoI)

CMOS Pixel Sensor using TowerJazz 0.18 μm CMOS Imaging Process

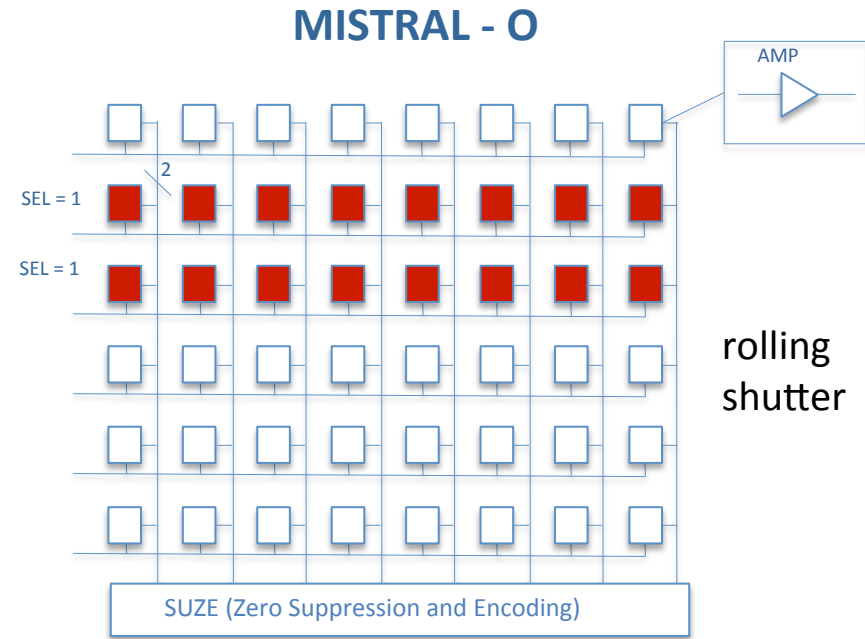
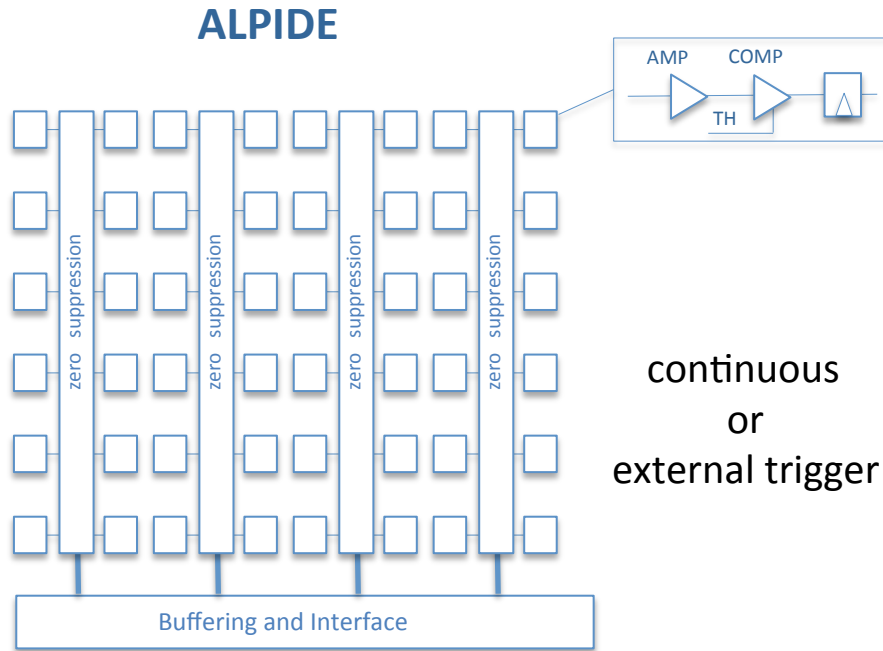


Tower Jazz 0.18 μm CMOS

- feature size 180 nm
- metal layers 6
- ➔ Suited for high-density, low-power
- Gate oxide 3nm
- ➔ Circuit rad-tolerant

- ▶ High-resistivity ($> 1\text{k}\Omega\text{ cm}$) p-type epitaxial layer (20 μm - 40 μm thick) on p-type substrate
- ▶ Small n-well diode (2-3 μm diameter), ~100 times smaller than pixel => low capacitance
- ▶ Application of (moderate) reverse bias voltage to substrate can be used to increase depletion zone around NWELL collection diode
- ▶ Quadruple well process: deep PWELL shields NWELL of PMOS transistors, allowing for full CMOS circuitry within active area

ITS Pixel Chip – two architectures

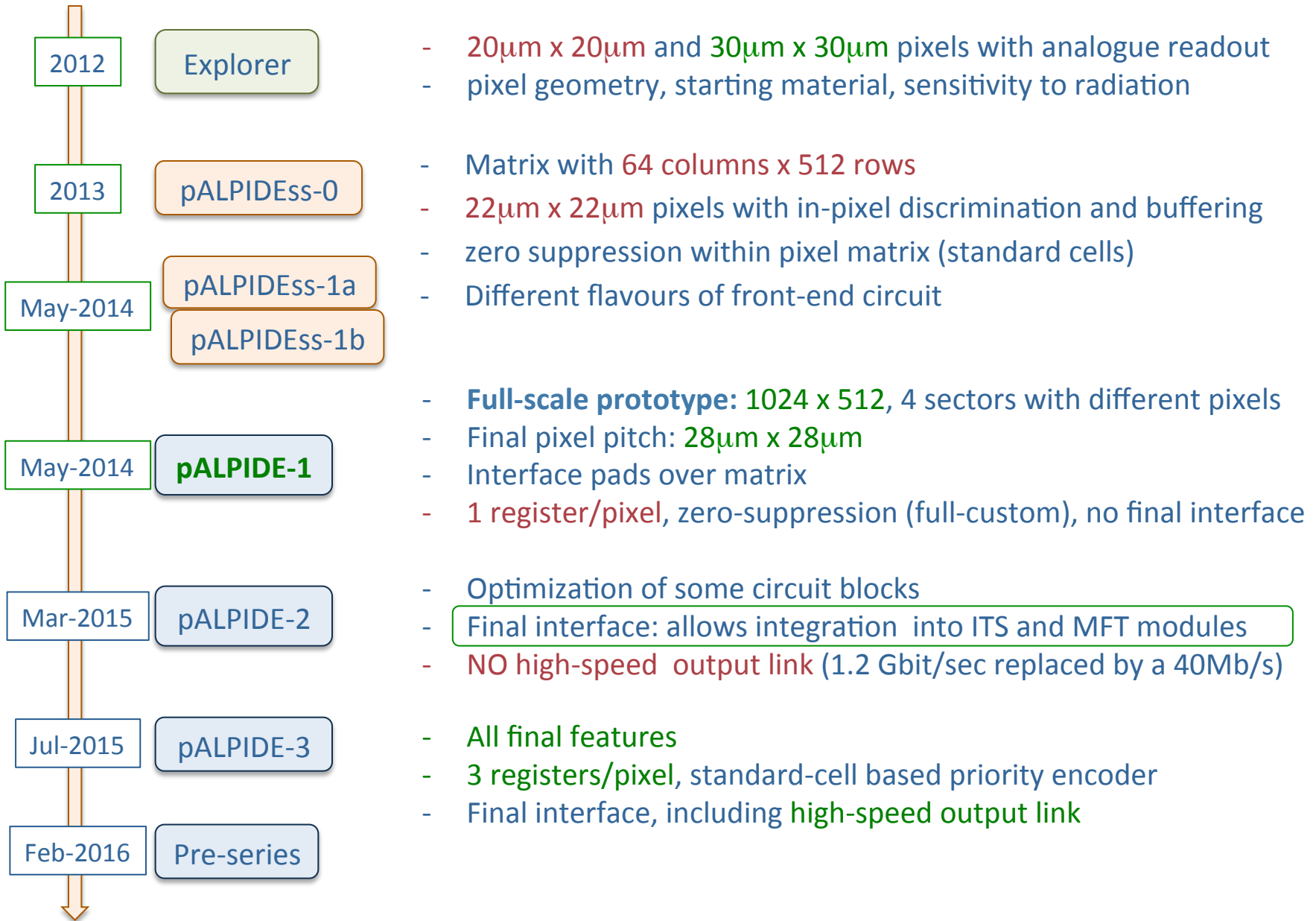


Pixel pitch	28 μ m x 28 μ m
Event time resolution	~2 μ s
Power consumption	39mW/cm ²
Dead area	1.1 mm x 30mm

Pixel pitch	36 μ m x 64 μ m
Event time resolution	~20 μ s
Power consumption ^(*)	97mW/cm ²
Dead area	1.7 mm x 30mm

ALPIDE and MISTRAL-O have same dimensions (15mm x 30mm), identical physical and electrical interfaces: position of interface pads, electrical signaling, protocol

(*) might further reduce to 73mW/cm²



pALPIDE-1 – Main Design Features

ALPIDE Full Scale prototype

- Dimensions: 30mm x 15 mm
- Pixel Matrix: 1024 cols x 512 rows
- Pixel pitch: $28\mu\text{m} \times 28\mu\text{m}$
- Peaking time: $2\mu\text{s}$
- Pulse length: 10-20 μs
- In-pixel discriminator + 1 register
- Power consumption: $< 40\text{mW}/\text{cm}^2$
- 4 sectors with different pixels

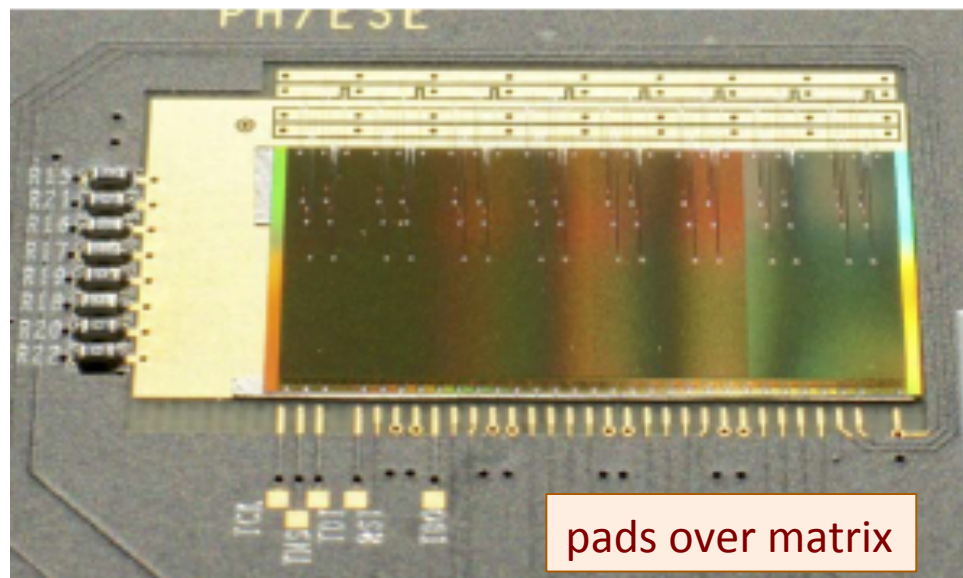
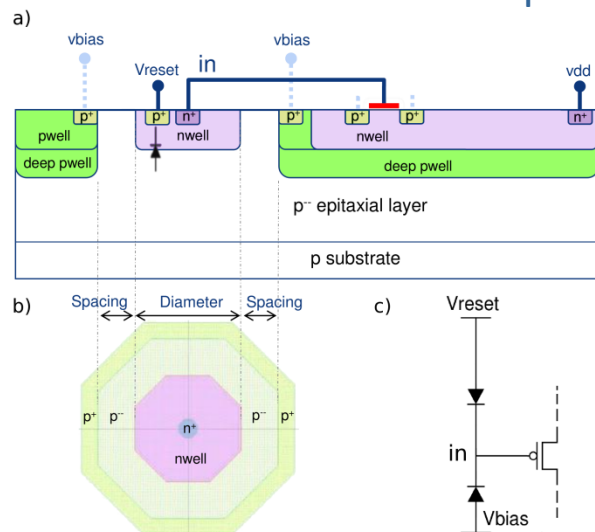


Figure: picture of pALPIDE-1



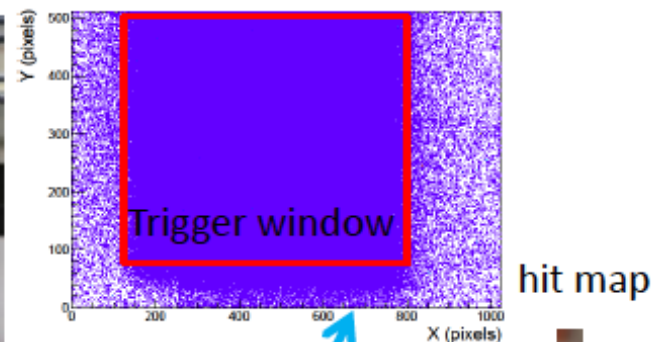
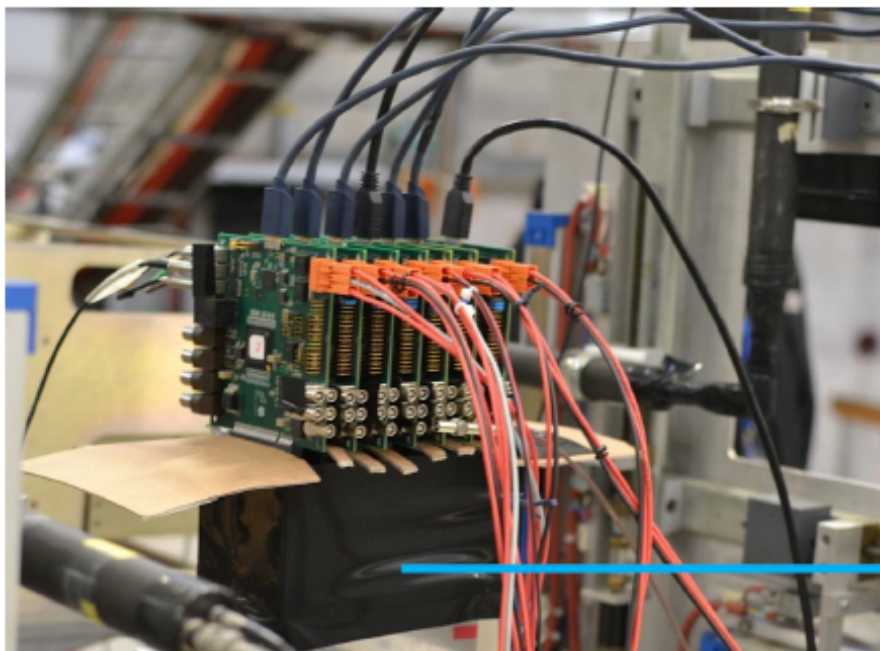
Sector	nwell diameter	spacing	pwell opening	reset
0	$2\mu\text{m}$	$1\mu\text{m}$	$4\mu\text{m}$	PMOS
1	$2\mu\text{m}$	$2\mu\text{m}$	$6\mu\text{m}$	PMOS
2	$2\mu\text{m}$	$2\mu\text{m}$	$6\mu\text{m}$	Diode
3	$2\mu\text{m}$	$4\mu\text{m}$	$10\mu\text{m}$	PMOS

Intensive test beam campaign

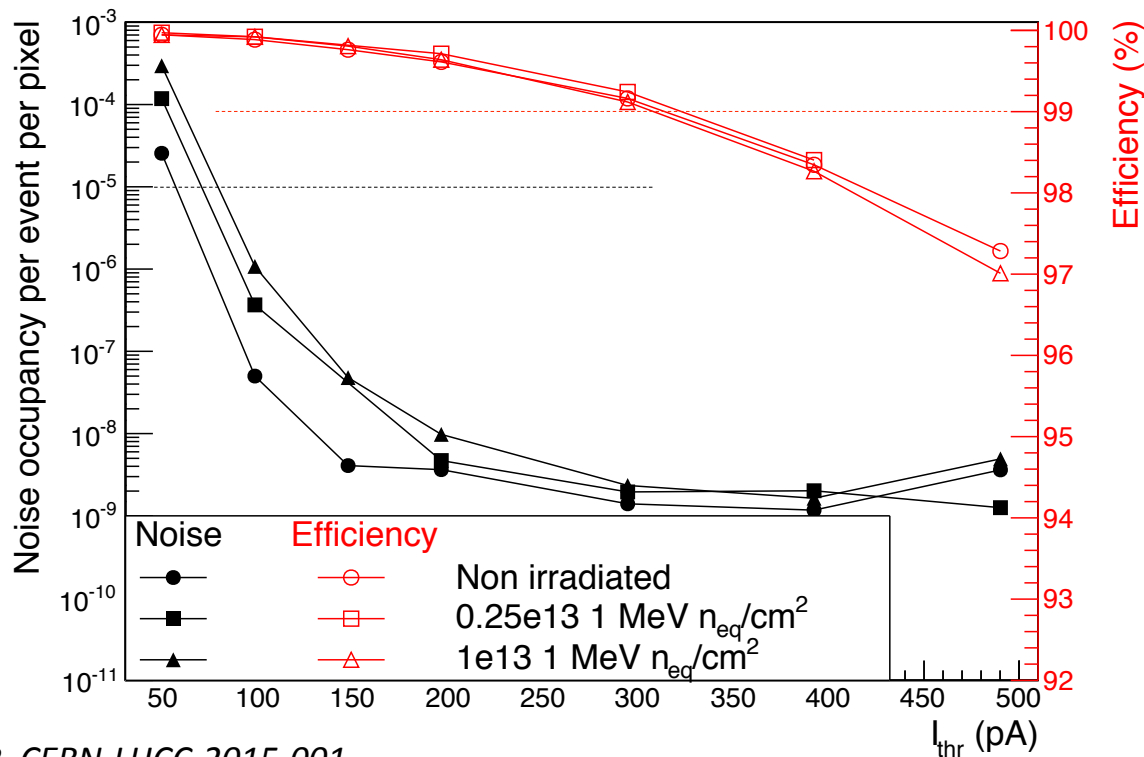
- PS: 5-7 GeV π^-
- SPS: 120 GeV π^-
- PAL (Korea): 60 MeV e^-
- BTF (Frascati): 450 MeV e^-
- DESY: 5.8 GeV e^+

Scan of main parameters → ~ 200 settings

7-plane telescope based on pALPIDE-1 chip



Efficiency and fake hit rate



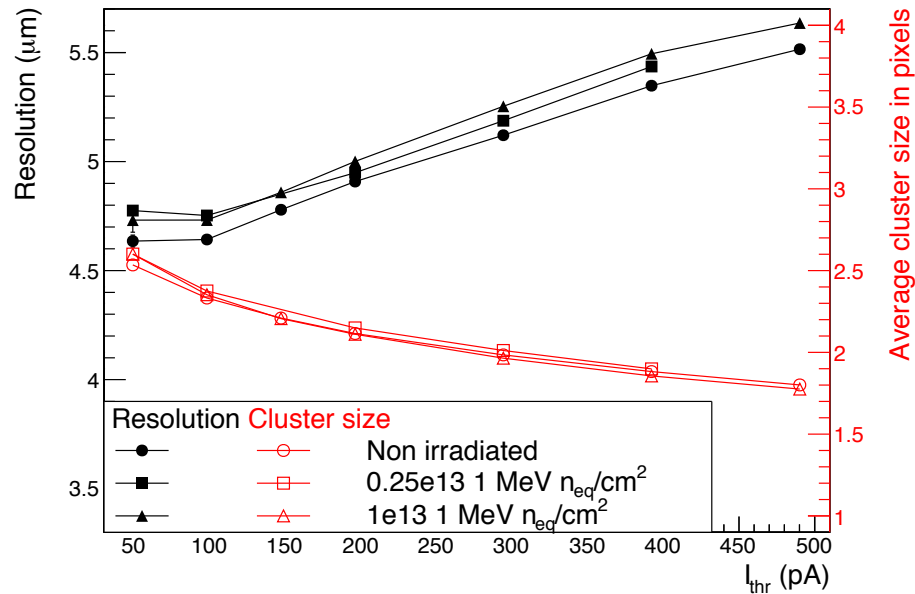
MFT TDR, CERN-LHCC-2015-001

50 pA → ~80 e
500 pA → ~180 e

$\lambda_{fake} < < 10^{-5} / \text{event/pixel} @ \epsilon_{det} > 99\%$ ➡ very large margin over design requirements

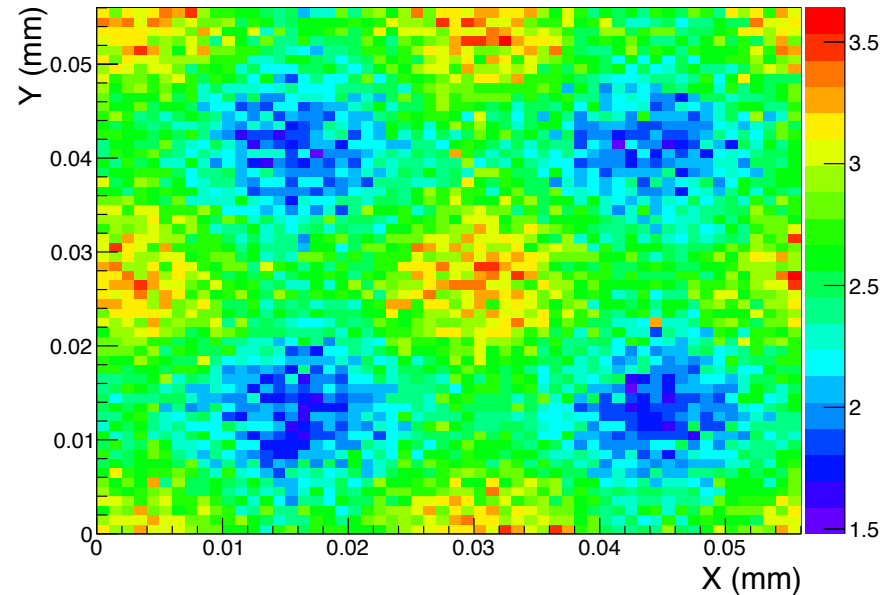
- Measurements at PS: 5 – 7 GeV π^- September 2014
- Results refer to 50 μm thick chips: non irradiated and irradiated with neutrons 0.25×10^{13} and 10^{13} 1MeV n_{eq} / cm^2

Spatial resolution



MFT TDR, CERN-LHCC-2015-001

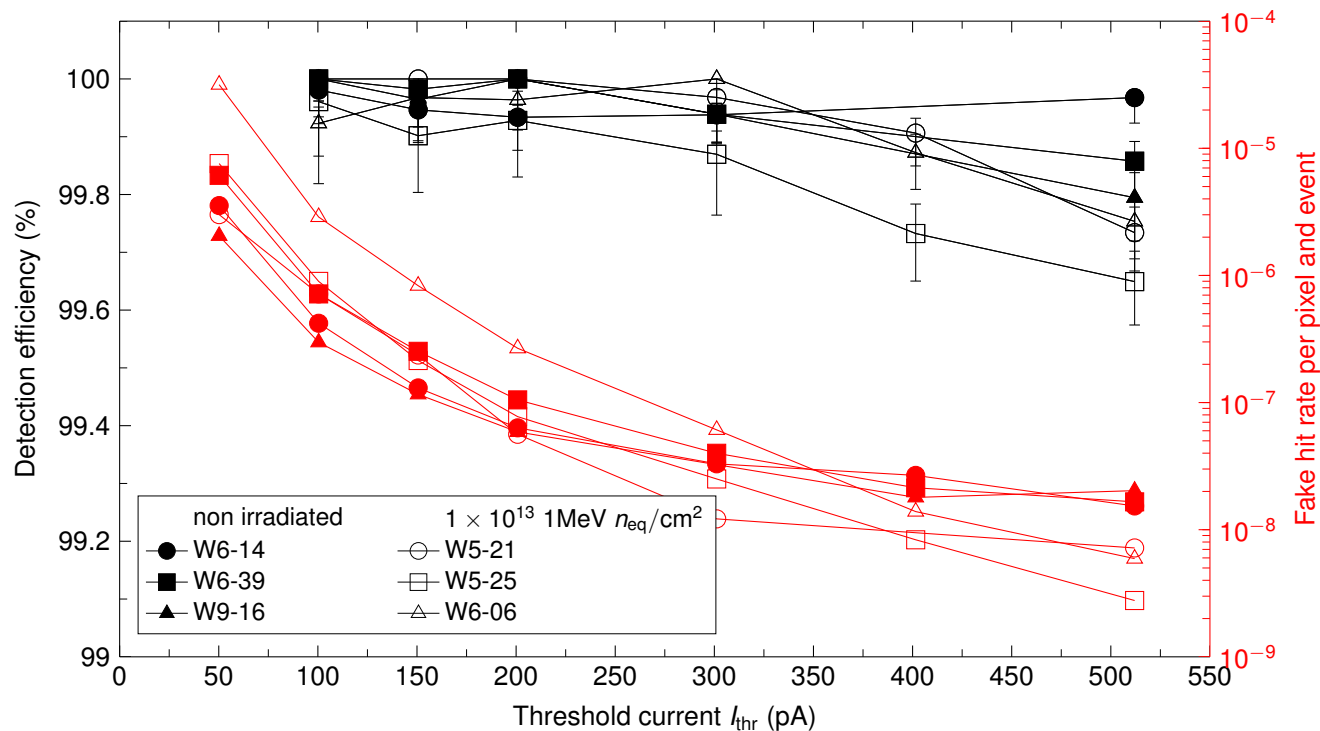
Cluster size vs. position within pixel



$\sigma_{\text{det}} < 5 \mu\text{m}$ is achieved with sufficient margin of operation

- Measurements at PS: 5 – 7 GeV π^- September 2014
- Results refer to 50 μm thick chips: non irradiated and irradiated with neutrons 0.25×10^{13} and 10^{13} 1MeV $n_{\text{eq}} / \text{cm}^2$

Efficiency and fake hit rate

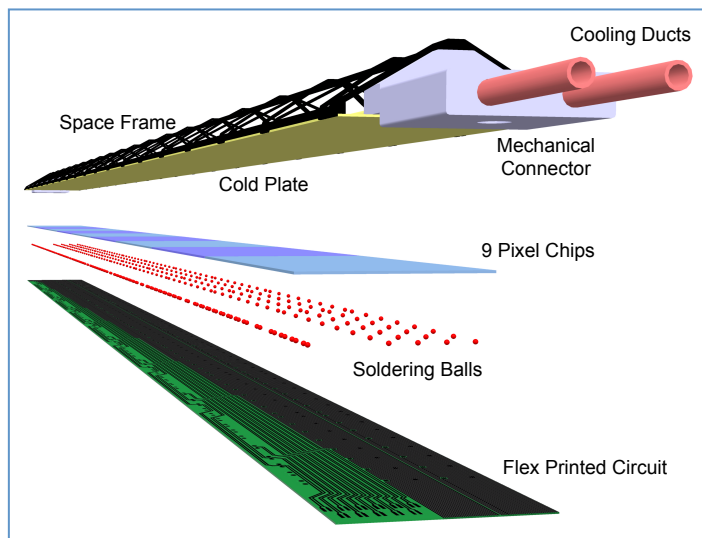
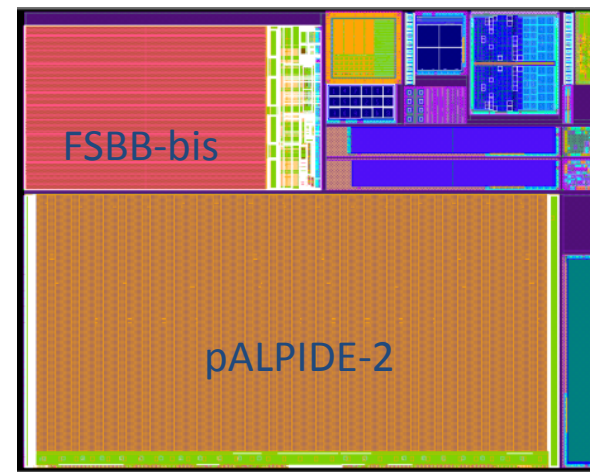


Improved test-beam data analysis

- Measurements at PS: 5 – 7 GeV π^- December 2014
- Results refer to 50 μ m thick chips: 3 non irradiated and 3 irradiated with neutrons

p-ALPIDE-2: 2nd full-scale prototype

- Optimization of some circuit blocks
- NO high-speed output link (1.2 Gbit/sec replaced by a 40Mb/s)
- Full Integration in IB and OB Module: main focus in 2015
- Delivery: mid March



p-ALPIDE-3: 3rd full-scale prototype

- Contains all final elements
- Submission: April '15 Delivery: July '15

p-ALPIDE-4: pre-series production

- Submission Dec '15



2011

Study of diode and in-pixel amplification

- MIMOSA-32, MIMOSA-32ter
- MIMOSA-32FEE, MIMOSA-32N
- MIMOSA-34 (study of large pixels, up to $22 \times 66 \mu\text{m}^2$)

2013

MISTRAL Readout Architecture

- MIMOSA-22THRa, MIMOSA-22THRb

MISTRAL FSBB-MO

- About 1/3 of final sensor based on small pixels ($22 \times 33 \mu\text{m}^2$)
- No pads over matrix
- Power consumption too high for Outer Barrel

May-2014

Sep-2014

MISTRAL Readout Architecture + large pixels (small matrix)

- MIMOSA-22THR(5-9)

MISTRAL-O

- 4 FSBB units with 208×208 large pixels of $36 \times 64 \mu\text{m}^2$
- Power consumption $\sim 100 \text{mW/cm}^2$
- Event time resolution (integration time) $20 \mu\text{s}$
- Pin-to-pin compatible with ALPIDE + common interface

Sep-2015

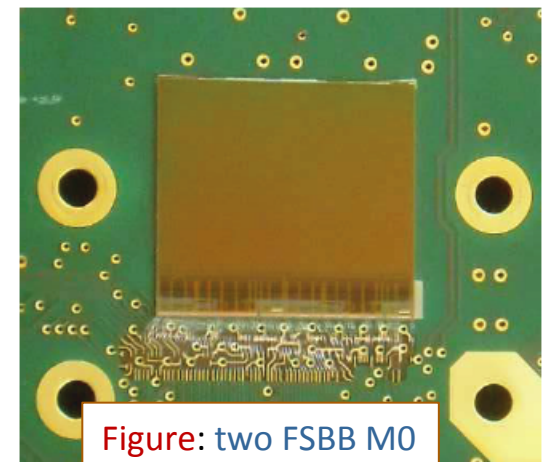
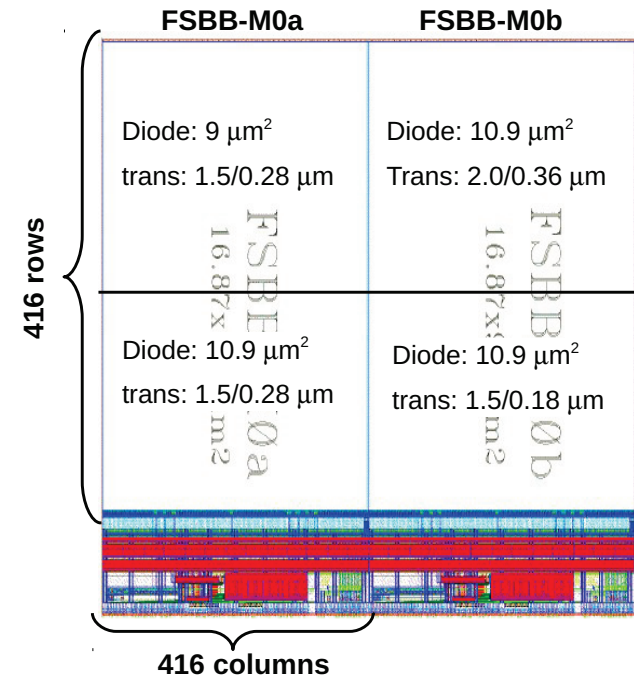
FSBB Main Features

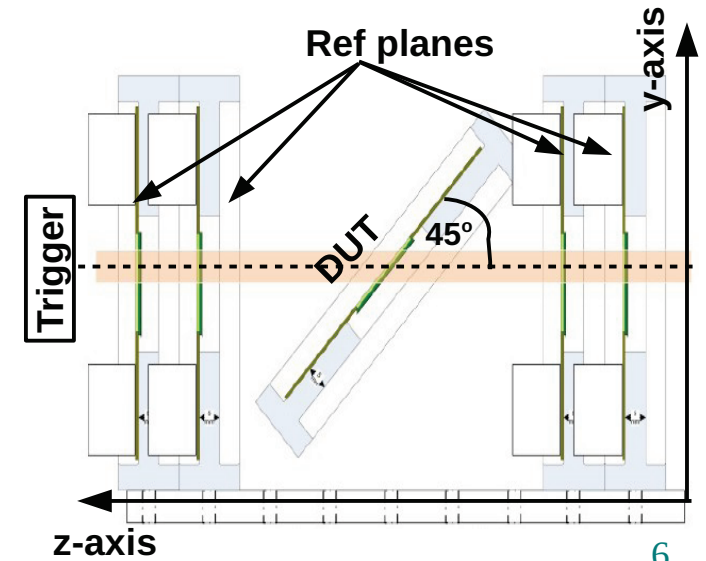
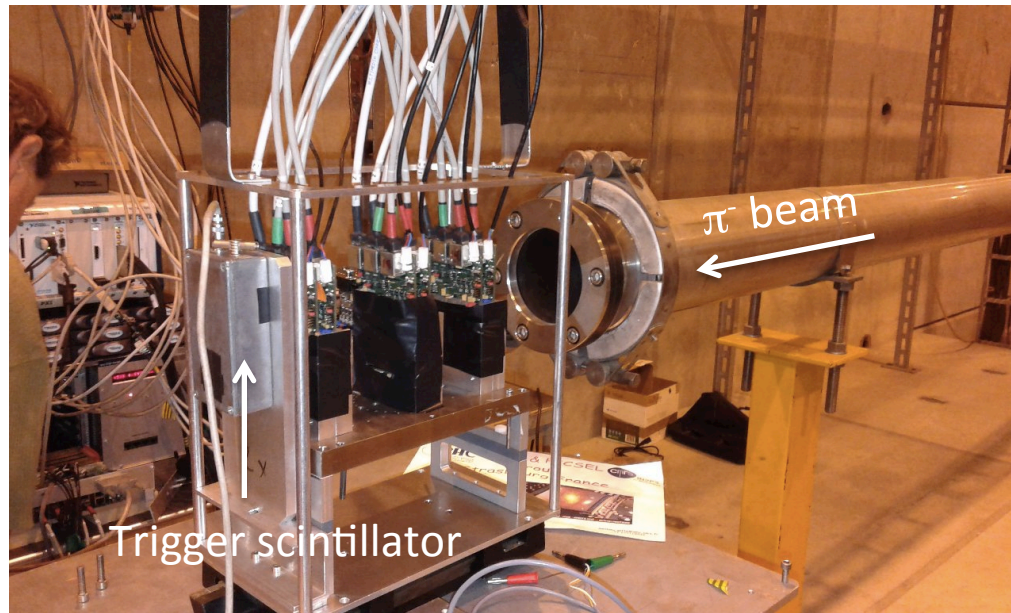
- About 1/3 of complete sensor (approx. 9mm x 17mm)
- Pixel Matrix: 416 Columns x 416 Rows
- Staggered Pixel: 22 μm x 33 μm (final chip 36 μm x 64 μm)
- In-pixel pre-amplification and clamping (6 metals)
- Double row-readout at 160MHz
- Integration time: 40 μs (final chip 20 μs)
- 2 versions (FSBB-M0 a & b): only results for M0-a will be shown

NB: the FSBB is not optimized in some respects (pixel dimensions, speed, power consumption, pads over matrix, ...)

Currently MISTRAL-O is being optimized for use in the outer layers:

- less need for spatial resolution: ~10 μm
- more stringent power consumption limit: < 100mW/cm²





Beam conditions

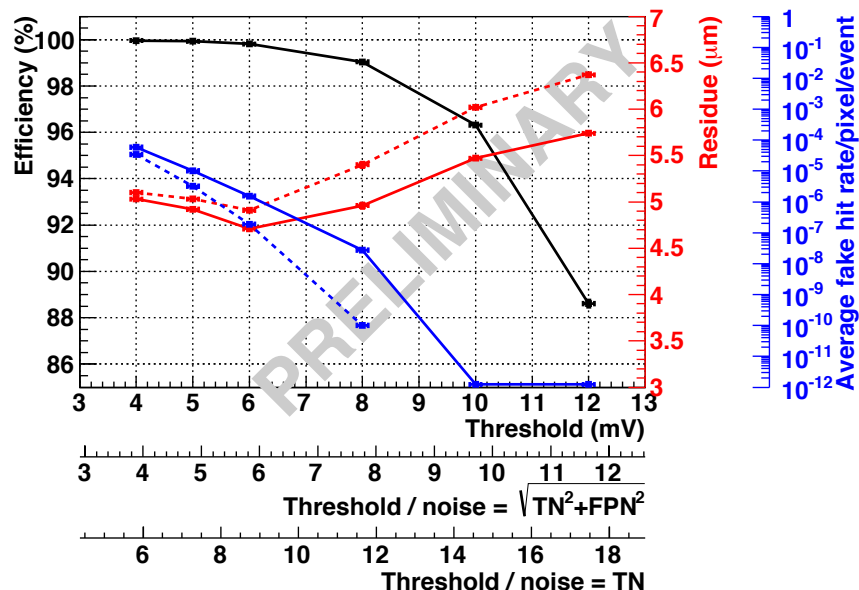
- SPS H6A area, 120 GeV π^-
- Particle flux: trigger rate in the range 2.5 to 100 kHz / $5 \times 10 \text{ mm}^2$

Device and operational conditions

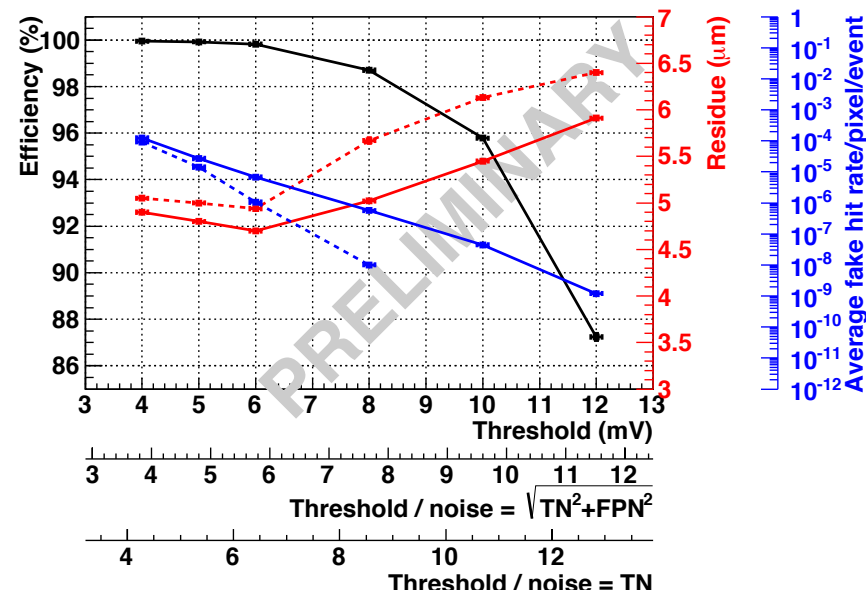
- 6 FSBB-M0a thinned to $50 \mu\text{m}$
- All measurements performed at $T_{\text{op}} = 30 \text{ }^\circ\text{C}$

MISTRAL FSBB-M0 – detection performance

FSBB_M0a, Diode = 9 μm^2 , Transistor = 1.5/0.28



FSBB_M0a, Diode = 10.9 μm^2 , Transistor = 1.5/0.28



Diode size (μm^2)	$\varepsilon_{\text{det}} \geq 99.8\%$	$\varepsilon_{\text{det}} \geq 99.5\%$	$\varepsilon_{\text{det}} \geq 99.0\%$	$\lambda_{\text{fake}}^{(*)} \leq 10^{-5}$
11	Thr ≤ 6.0 mV	Thr ≤ 6.5 mV	Thr ≤ 8.0 mV	Thr ≥ 6.0 mV
9	Thr ≤ 6.0 mV	Thr ≤ 7.0 mV	Thr ≤ 8.0 mV	Thr ≥ 5.0 mV

- (*)
- Fake rate drops by O(10) masking 20 noisiest pixels.
 - Final chip includes masking feature

ALPIDE

- Full-scale prototype (p-ALPIDE-1) includes most of final features
- Extensive characterization shows large margin over design requirements
- Integration of chip into detector modules starts in Apr '15 till Dec '15
- Pre-series production starts Dec '15
- 🖱️ Project baseline ... however full validation will take till end of 2015

MISTRAL-O

- Optimized for Outer Barrel layers
- MISTRAL FSBB-M0 (small pixel pitch) shows also very good performance
- Submission of full-scale prototype with all final features: July '15
- Integration into detector modules starts Oct '15

The full pin-to-pin compatibility allows switching from ALPIDE to MISTRAL-O with minimum overhead on production and test plans ...

... implication of reduced spatial resolution for the IB need to be studied but expected to be small

SPARES

Spatial resolution

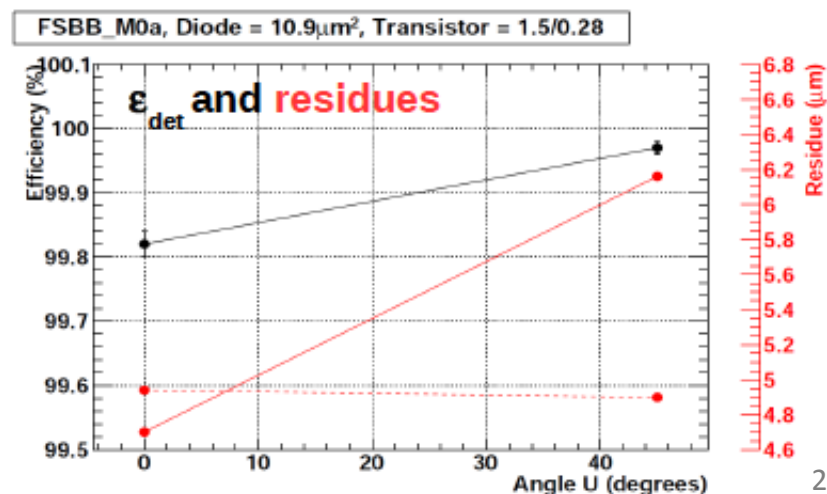
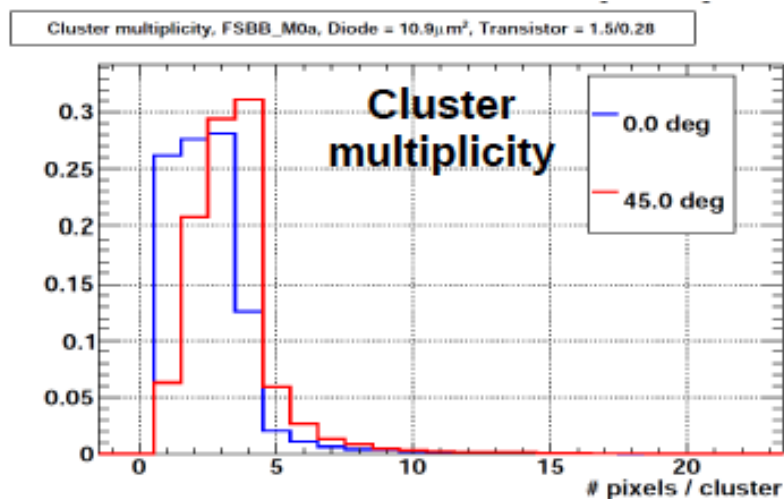
- Track reconstruction using all telescope planes but the device under test (DUT)
- Residual (DUT): $\sigma_{\text{res}} \approx (4.7 \pm 0.1) \mu\text{m}$ (U) & $(4.9 \pm 0.1) \mu\text{m}$ (V) at 6mV for both diodes
- Expected Resolution (removing telescope tracking error): $\sigma_{\text{sp}} \approx 4.5 \mu\text{m}$

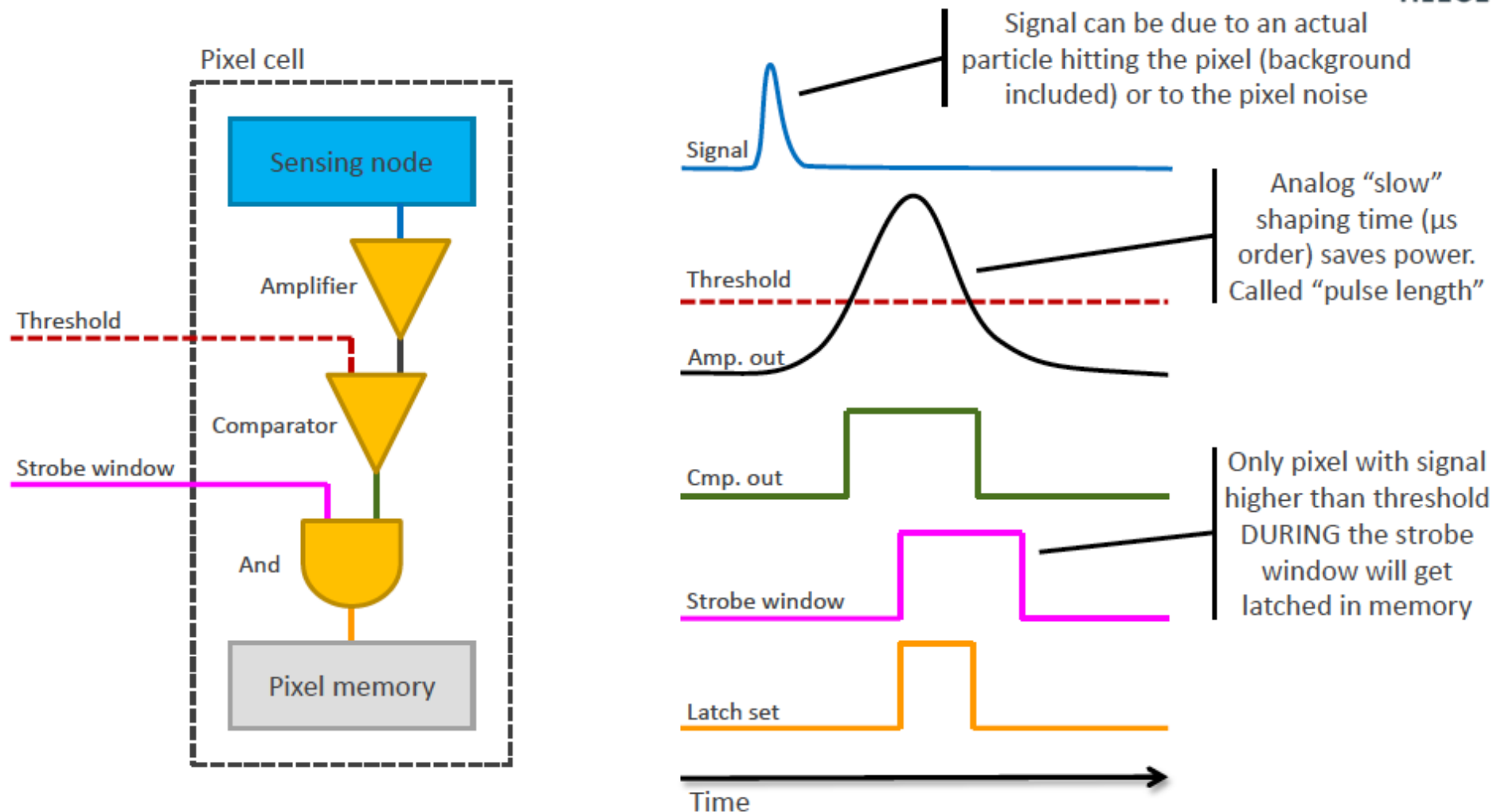
NOTE: FSBB pitch 22 μm x 33 μm MISTRAL-O pitch 36 μm x 64 μm

Sensitivity to trigger rate

- ϵ_{det} , λ_{fake} , σ_{sp} are not sensitive to trigger rate (measured in the range 25-100 kHz)

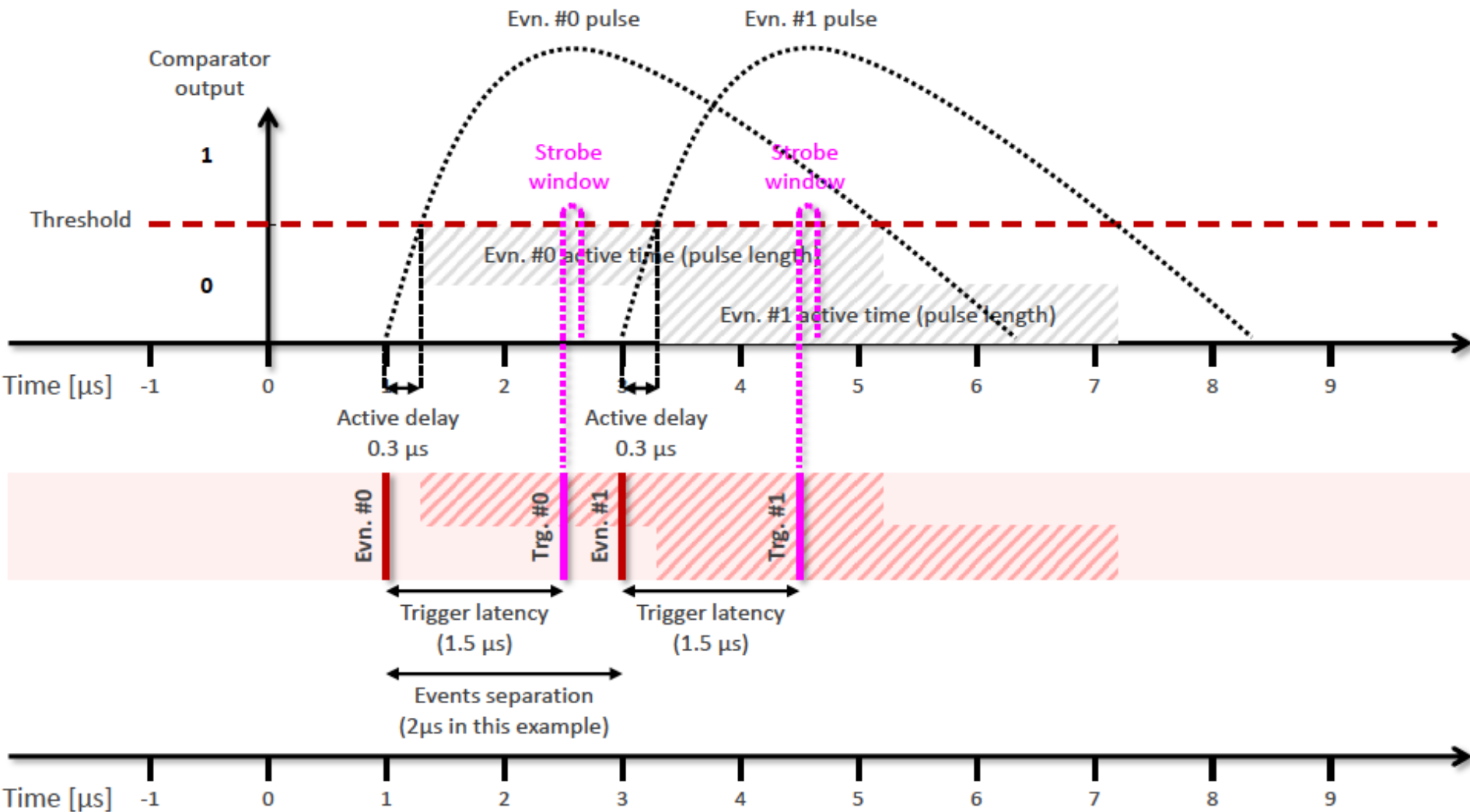
Detection performance at high incidence angles



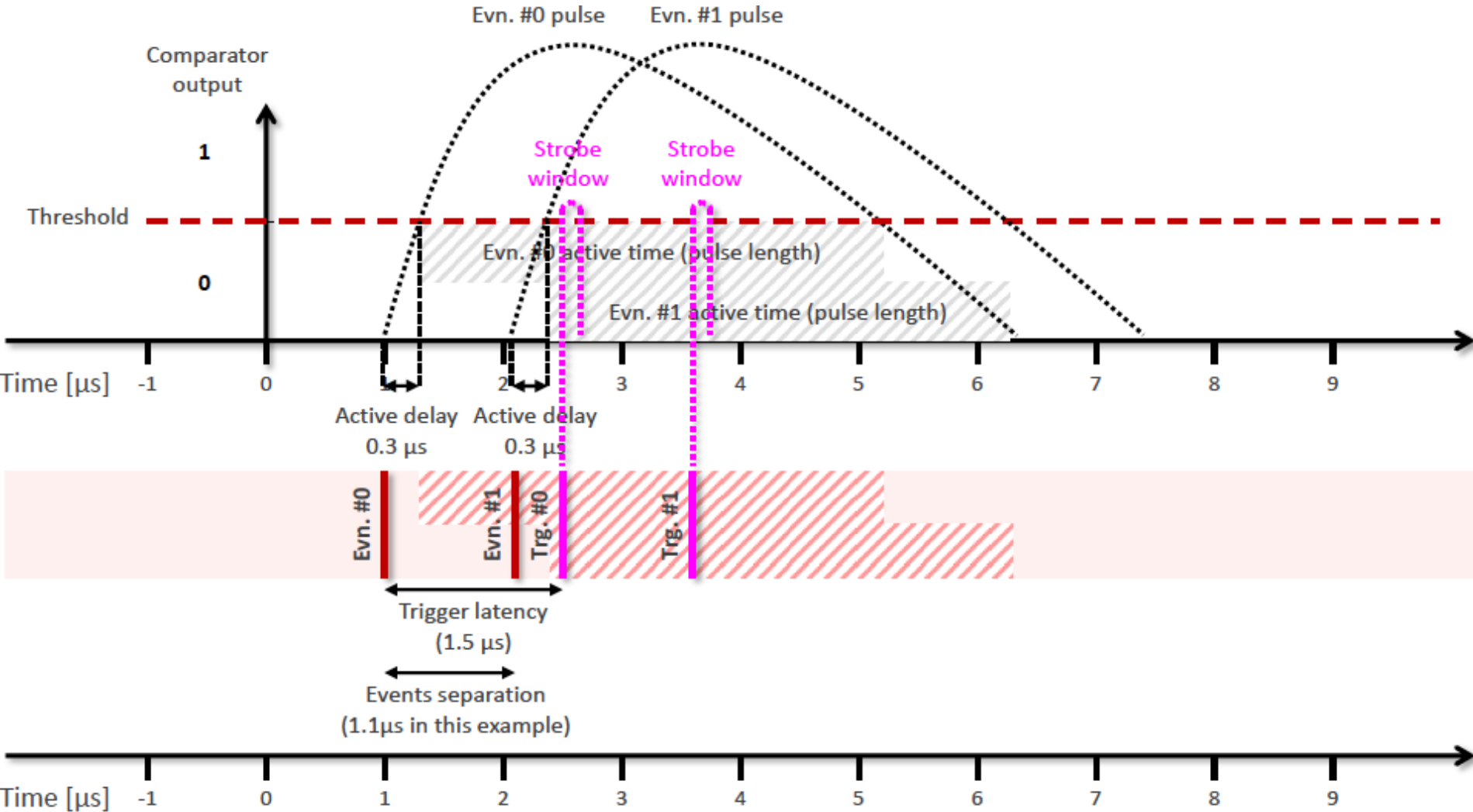


Bottom line: whichever signal high enough to trigger the comparator during the strobe windows is saved. Due to the analog shaping time, this means signals generated up to a certain time before the strobe window will be saved as well.

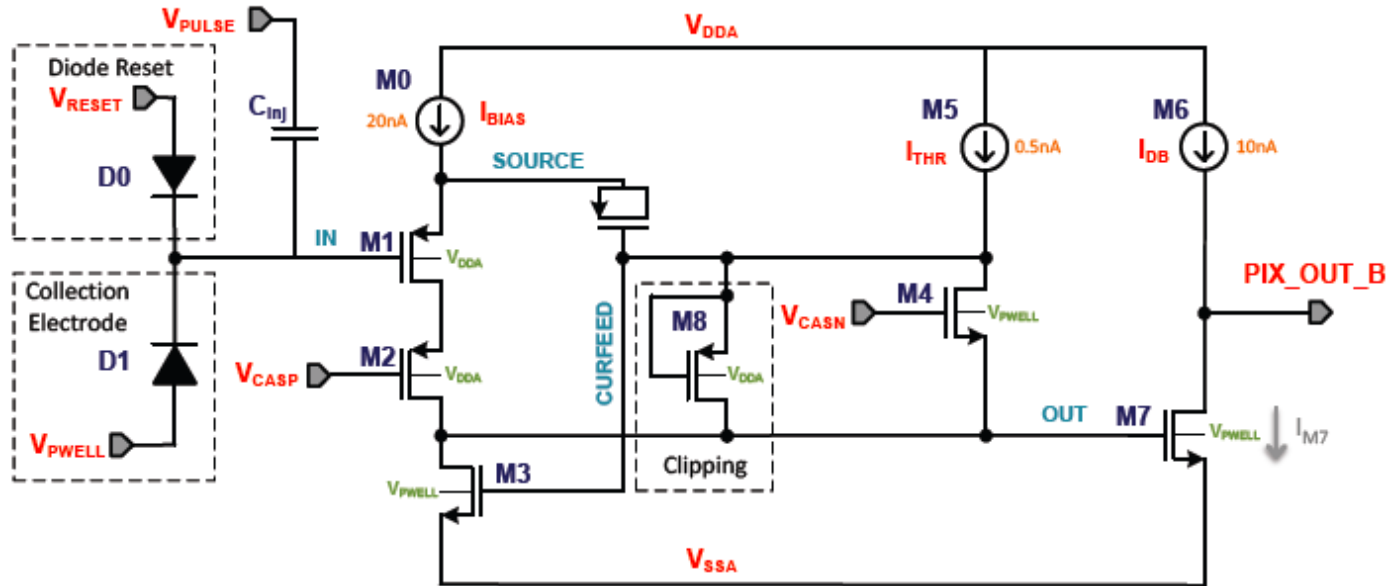
ALPIDE – Timing (2/3)



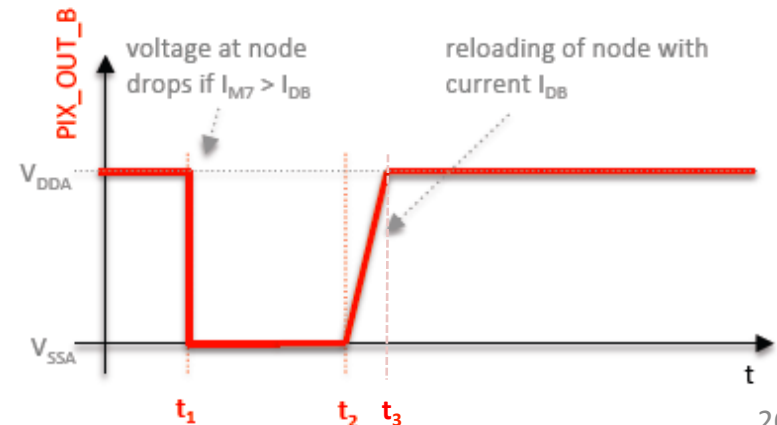
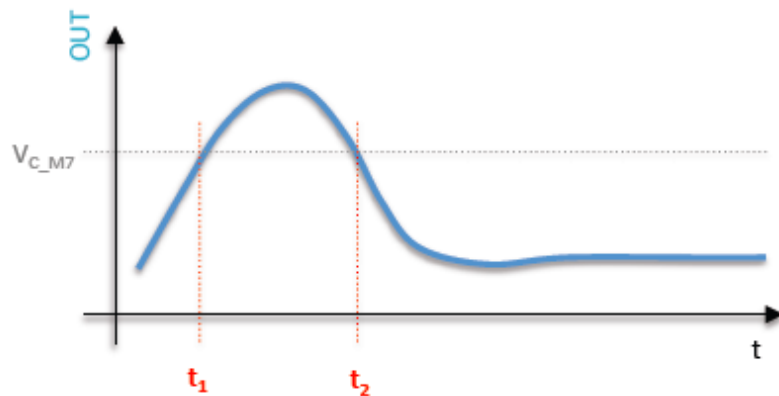
ALPIDE – Timing (3/3)

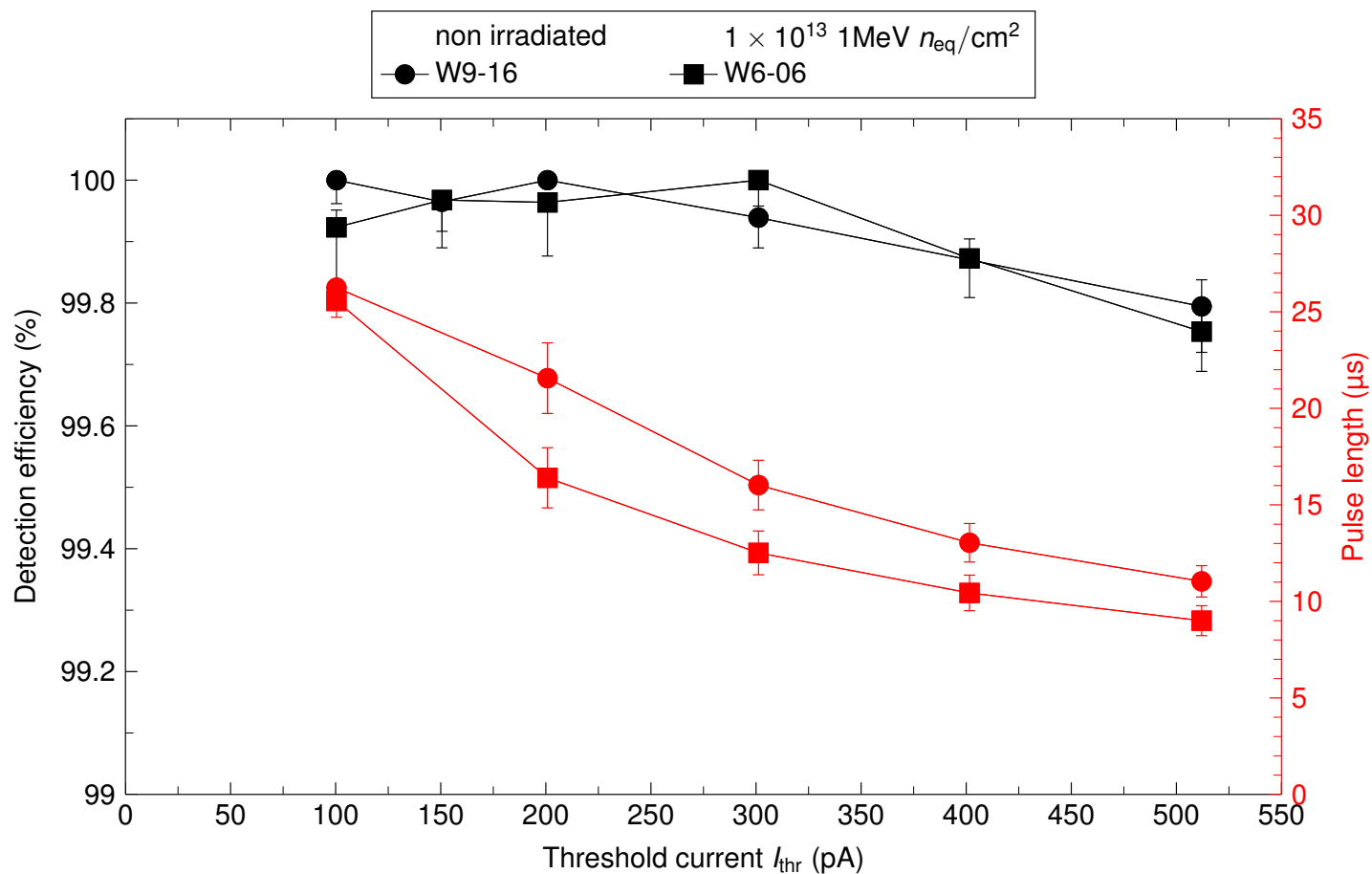


► Schematic:



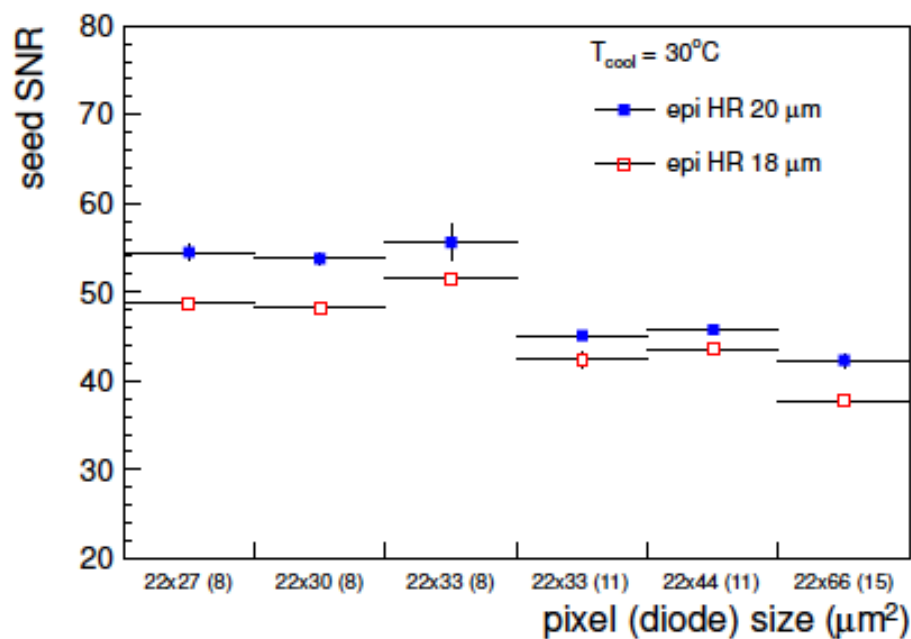
► Principle:



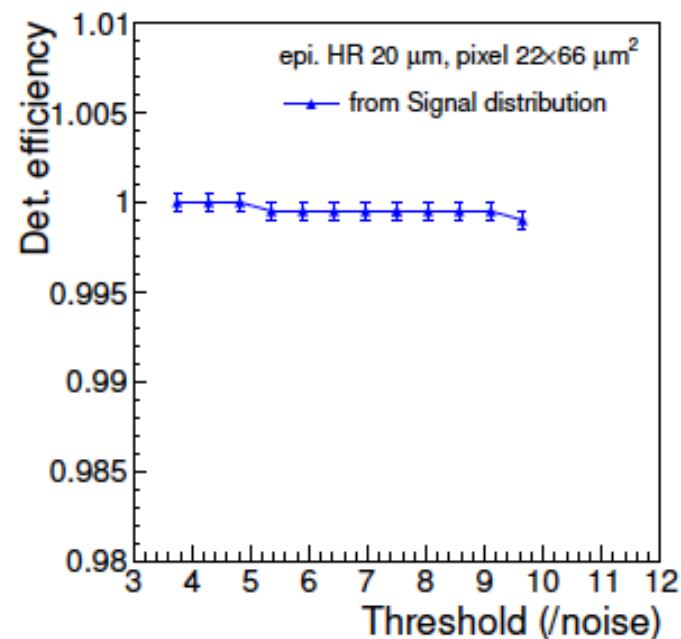


Measurement of threshold current versus pulse length and detection efficiency

ITS Upgrade TDR, CERN-LHCC-2013-24



(a) Seed SNR (MPV) for various pixel geometries, for the HR-18 and HR-20 epitaxial layers



(b) Detection efficiency for the 22 $\mu\text{m} \times 66 \mu\text{m}$ pixel

Figure 2.12: MIMOSA-34 results.

- SEL refers to a short of the supply planes induced by ionizing particles
 - Sensor needs to be protected (switched off quickly) to avoid damage
 - Power cycle needed to recover (impact on operation)
- SEL is a threshold effect depending on the linear energy transfer (LET)
 - Only recoils from nuclear reactions of primary particles with silicon have LETs that can cause SELs
 - So far, the effect is studied in the lab with heavy ions from a cyclotron to obtain the LET threshold and to identify weak parts of the circuits
 - Tests with high flux protons are foreseen
- Two structures were characterized for SEL
 - Memory chip: dense structures like memories are typically most susceptible to SEL
 - pALPIDE-1
- Collimators were used to identify weak spots:
 - Single-port memories will not be used
 - The analogue biasing of pALPIDE-2 will be improved wrt pALPIDE-1

Single Event Latch-up (SEL)

Measurements done at Louvain-la-Neuve

